

Abstract

[0026]

A method and a system for testing circuits of an AMOLED before implantation of OLEDs are provided. Each circuit includes a terminal, connected to an OLED after the OLED is implanted, configured as a test point. The system selects one circuit to test. The method and the system extract a current signal from the test point, and then analyze it to determine the status of the circuit. The steps being repeated, all circuits of the AMOLED can be tested efficiently and precisely.